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Complete if Known Substitute for form 1449B/PTO INE DRMATION DISCLOSURE 10/689,547 Applicati n Numb r JUL 2 1 2004 OF THE STATEMENT BY APPLICANT 10/21/2003 Filing Dat First Named Inventor Percy Van Crocker 7/21/04 Date/Submitted: 2012 1756 **Group Art Unit** John Ruggles ás many sheets as necessary) **Examiner Name Unassigned** of Attorney Docket Number 083847-0198

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	INFORMATION DISCL	.OSURE	Applicati n Number	10/689,547			
	STATEMENT BY APP		Filing Date	10/21/2003			
	Date Submitted: 7/	21/04	First Named Inventor	Percy Van Crocker			
7	Date Submitted:		Group Art Unit	2012 1756			
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Sh et	2 of		Attorney Docket Number	083847-0198			

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Date Submitted: October 25, 2005

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Application Number	10/689,547	
Filing Date	10/21/2003	
First Nam d Inv ntor	Crocker	
Group Art Unit	1756	
Examiner Name	Ruggles	
Attorney Docket Number	083847-0198	

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	Date Submitted	3: October 4	25, 2005	Group Art Unit	1756	
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Sheet	2	of	3	Attorney Docket Number	083847-0198	

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Sheet	3	of 3	Attorney Docket Number	083847-0198	4

		NON PATENT LITERATURE DOCUMENTS
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	TATEMENT			Filing Date	10/21/2003		
				First Named Inventor	Percy VAN CROCKER et al.		
				Group Art Unit	1756		
(use	as many she	eets as nece:	ssary)	Examiner Name	John S. Ruggles		
Sheet	1	of	1	Attorney Docket Number	083847-0198		

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